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Data Sheet

August 15, 2026

AGILENT / KEYSIGHT

Agilent / Keysight E1740A Time Interval Analyzer Module

HP Agilent E1740A Time Interval Analyzer VXI Module The HP E1740A isaC-size VXI time-interval analyzer module. OEM E1740A product data list time-interval, frequency, and jitter-class measurements in a VXI slot for ATE, with HP-IB/VXI programming via a command module, used for clock and data timing analysis in communications and digital systems. Time-interval and jitter measurements in VXI automated test systems. Instrument Type: Time interval analyzer module The HP E1740A isaC-size VXI time-interval analyzer module. OEM E1740A product data list time-interval, frequency, and jitter-class measurements in a VXI slot for ATE, with HP-IB/VXI programming via a command module, used for clock and data timing analysis in communications and digital systems. Time-interval and jitter measurements in VXI automated test systems. Instrument Type: Time interval analyzer module Measurements: time interval frequency and jitter class



MODEL Agilent / Keysight E1740A	CALIBRATION Available on request
CONDITION Used	STATUS In stock
RFQ / SKU E1740A	LISTING https://aumictechlabs.com/products/e1740a-2/

NIST-traceable cal

SAM registered

30-day returns

NAICS 423690 • 811210 • 541380

This unit

The Agilent/Keysight E1740A is a 2-slot, C-Size VXI time interval analyzer module delivering high-resolution timing measurements for precision jitter characterization and synchronization analysis. This message-based, SCPI-compatible card forms the core component of the E1725C VXI system

and rapidly collects large datasets into histograms, enabling statistically solid timing analysis across edge capture and pulse series configurations.

Technical Specifications

Form Factor: 2-slot, C-Size VXI module

Interface: Message-based VXI, SCPI compatible

Edge Timing Rates (configuration-dependent):

- Up to 80 MHz pulse series with 12.5 ns minimum continuous interval and 3.2 μ sec maximum interval
- Up to 40 MHz edge capture with 25 ns minimum continuous interval and 104 ms maximum interval

Data Collection: High-speed histogram acquisition supporting large sample populations for enhanced statistical confidence

Key Features

- High-resolution timing capture with sub-nanosecond precision
- Flexible measurement modes for both pulse and edge-based timing analysis
- Rapid data aggregation into statistical distributions
- Integrated within E1725C systems for modular timing test solutions

Typical Applications

- Jitter characterization and clock distribution analysis
- Telecommunications and SONET/SDH timing validation
- VCO/PLL phase noise and stability measurement
- Network synchronization verification
- Data storage device timing performance
- Radar and surveillance system timing analysis
- Digital design timing closure and validation
- High-speed mechanical system synchronization

Compatibility & Integration

The E1740A integrates directly into VXI chassis architectures and operates under SCPI control. Compatible with HP E1742A/43A/44A/46A/48A analysis software packages for application-specific measurement automation and reporting.

E1740A Characteristics / Specifications

PARAMETER	VALUE
Model	E1740A
Instrument Type	Time interval analyzer module
Module Size	C-size VXI
Measurements	time interval frequency and jitter class
Host Mainframes	E1401-class C-size VXI
Control	VXI via Slot 0 command module
Manufacturer	HP Agilent Keysight
Mechanical Package	VXI plug-in module
Application Class	clock and data timing ATE
Documentation	HP E1740A time interval analyzer module data
Programming	register/message based via command module
Duty	continuous timing analysis
Related Command Module	E1405A E1406A
Platform	VXIbus
Function	time interval analysis
Use Case	communications and digital timing
Grounding	VXI chassis ground
Power	from VXI backplane
Slot Width Class	C-size as published for E1740A
System Family	HP VXI measurement modules
Display	via controller/command module UI
Ate Interface	VXI/HP-IB
Measurement Domain	time and frequency

E1740A Specifications

PARAMETER	VALUE
HP Agilent E1740A Time Interval Analyzer VXI Module	Overview
Frequency and TI measurements	ATE clock/data timing
Technical Specifications	Model: E1740A

Full OEM specifications

Complete technical content extracted from the manufacturer datasheet. Sparse OEM tables are reconstructed as tables below; other text is preserved as paragraphs.

Specifications	
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Notes	
From HP E1740A VXI time-interval analyzer module product data. Resolution and maximum frequency are on the E1740A specification sheet matching the serial.	

Available from Aumictech

Used and refurbished unit evaluated in-house. Calibration: Available on request. Used · In stock.

Request a quote: sales@aumictech.com · +1 (484) 841-9341

Aumictech

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Technical content from manufacturer specifications. Unit photo/stock from Aumictech listing when available. Specifications subject to OEM documentation and unit condition.